

#### Cambridge International AS & A Level

PHYSICS
Paper 5 Planning, Analysis and Evaluation
February/March 2025
MARK SCHEME
Maximum Mark: 30
Published

This mark scheme is published as an aid to teachers and candidates, to indicate the requirements of the examination. It shows the basis on which Examiners were instructed to award marks. It does not indicate the details of the discussions that took place at an Examiners' meeting before marking began, which would have considered the acceptability of alternative answers.

Mark schemes should be read in conjunction with the question paper and the Principal Examiner Report for Teachers.

Cambridge International will not enter into discussions about these mark schemes.

Cambridge International is publishing the mark schemes for the February/March 2025 series for most Cambridge IGCSE, Cambridge International A and AS Level components, and some Cambridge O Level components.

#### **Annotations guidance for centres**

Examiners use a system of annotations as a shorthand for communicating their marking decisions to one another. Examiners are trained during the standardisation process on how and when to use annotations. The purpose of annotations is to inform the standard isation and monitoring processes and guide the supervising examiners when they are checking the work of examiners within their team. The meaning of annotations and how they are used is specific to each component and is understood by all examiners who mark the component.

We publish annotations in our mark schemes to help centres understand the annotations they may see on copies of scripts. Note that there may not be a direct correlation between the number of annotations on a script and the mark awarded. Similarly, the use of an annotation may not be an indication of the quality of the response.

The annotations listed below were available to examiners marking this component in this series.

#### **Annotations**

Annotation	Meaning
Ŷ	information missing or insufficient for credit
BOD	benefit of the doubt given
×	incorrect point or mark not awarded
ECF	error carried forward applied
МО	methods of data collection mark
Р	defining the problem mark
SEEN	blank page seen
SF	error in number of significant figures

Annotation	Meaning		
✓	orrect point or mark awarded		
I	ignore the response		
R	repeat of point previously awarded mark		
U	incorrect unit		
<b>✓</b> 1	correct awarding one mark from additional detail 1. similar numbered ticks are used for additional detail 2, 3, 4 etc.		

Answer	Marks		
Defining the problem			
Vary $p$ and measure $B$ OR $p$ is the independent variable and $B$ is the dependent variable.			
Keep V constant or potential difference between the ends of each conductor constant.	1		
Methods of data collection			
<ul> <li>Labelled diagram of workable experiment including:</li> <li>conductors in parallel connected in series to power supply and resistor</li> <li>circuit symbols for (variable) resistor and power supply</li> <li>X labelled and one other label from L, P, Q, p and q.</li> </ul>			
Voltmeter connected in parallel with conductors (to measure <i>V</i> ) and conductors in parallel connected to a power supply.			
Method to measure $L$ and $p$ and $q$ e.g. use a rule / ruler / calipers.			
Method to measure B, e.g. use a (calibrated) Hall probe <b>and</b> adjust / rotate probe until <u>maximum</u> value.			
Method of Analysis			
Plots a graph of $B$ against $\frac{1}{\rho}$ or equivalent. Do not accept logarithms.			
$B \text{ against } \frac{1}{p} \qquad \qquad \frac{1}{p} \text{ against } B$ $Y = \frac{L \times \text{gradient}}{AV} \qquad Y = \frac{L}{AV \times \text{gradient}}$	1		
	Defining the problem         Vary p and measure B OR p is the independent variable and B is the dependent variable.         Keep V constant or potential difference between the ends of each conductor constant.         Methods of data collection         Labelled diagram of workable experiment including: <ul> <li>conductors in parallel connected in series to power supply and resistor</li> <li>circuit symbols for (variable) resistor and power supply</li> <li>X labelled and one other label from L, P, Q, p and q.</li> </ul> Voltmeter connected in parallel with conductors (to measure V) and conductors in parallel connected to a power supply.         Method to measure L and p and q e.g. use a rule / ruler / calipers.         Method to measure B, e.g. use a (calibrated) Hall probe and adjust / rotate probe until maximum value.         Method of Analysis         Plots a graph of B against 1/p or equivalent.         Do not accept logarithms.		

Question	Answer			Marks
1	B against $\frac{1}{p}$	$\frac{1}{p}$ against $B$		1
	$Z = \frac{q \times y \text{-intercept}}{\text{gradient}}$ OR $Z = \frac{Lq \times y \text{-intercept}}{\sqrt{2q}}$	$Z = -q \times y$ -intercept		
	- YAV			
	Additional detail included Any six from:	ding safety consider	ations	6
	D1 precaution linked to <a href="https://high.current/hot.conductors">high.current/hot.conductors</a> , e.g. use gloves / switch off power supply when not measuring B/ between measurements / allow conductors to cool			
	D2 keep A and L and q constant			
	D3 use calipers / micrometer to measure diameter / $d$ of conductor <b>and</b> $A = \frac{\pi d^2}{4}$			
	D4 repeat measurements of d in different positions and average d			
	D5 method to determine the position of X in relation to the conductors, e.g. divide L by two to find the midpoint of P / Q and use a set square / protractor / plumb line to mark X OR divide L by two to find the midpoint of P / Q and use a grid to mark X			
	D6 measure <i>B</i> (using Hall probe) first in one direction and then in the opposite direction and average <i>B</i> OR Measure <i>B</i> with current / p.d. in one direction and then in the opposite direction and average <i>B</i>			
	D7 additional detail on r	measuring $p$ and $l$ or $q$ ,	e.g. measure to the conductor and add on the radius	

Question	Answer	Marks
1	D8 description of method to keep $q$ constant, e.g. tape / adhesive putty to fix conductor Q to the bench OR for vertical methods fix conductor Q in clamp(s) attached to stand(s) to keep $q$ constant	
	D9 method to keep P and Q parallel, e.g. measure the separation (between the conductors) at different points	
	D10 relationship valid <u>if</u> a straight line is produced (with a <i>y</i> -intercept = $\frac{YZAV}{Lq}$ ).  Do not accept passing through the origin.	
	D11 method to keep V constant, e.g. adjust / change variable resistor / power supply to keep voltmeter reading constant.	

Questio	Answer	Marks
2(a)	gradient = $-\frac{1}{K}$ y-intercept = $\ln(\theta_0 - \theta_R)$	1

Question			Answer	Marks
2(b)	( <i>θ</i> − <i>θ</i> κ)/°C	In (( <i>θ</i> − <i>θ</i> κ) / °C)		
	56.5 ± 1.0	4.034 or 4.0342 ± 0.018		
	46.0 ± 1.0	3.829 or 3.8286 ± 0.022		
	38.5 ± 1.0	3.651 or 3.6507 ± 0.026		
	31.5 ± 1.0	3.450 or 3.4500 ± 0.032		
	26.0 ± 1.0	3.258 or 3.2581 ± 0.038		
	22.5 ± 1.0	3.114 or 3.1135 ± 0.044		
	Values of $(\theta - \theta R)$	$/^{\circ}$ C and In $((\theta - \theta_R)/^{\circ}C)$		1
	Uncertainties in ( $\theta$	$\theta - \theta_R$ ) and In $((\theta - \theta_R) / {^{\circ}C})$		1
2(c)(i)	Six points from (b Must be within ha	) plotted correctly. If a small square. Diameter c	f points must be less than half a small square.	1
		$(\theta-\theta_{\rm R})/^{\circ}{\rm C})$ plotted correctly plotted. Total length of bar	must be accurate to less than half a small square and symmetrical.	1

Question	Answer	Marks
2(c)(ii)	Straight line of best fit drawn.  Do not accept line from top plot to bottom plot.  Line must pass between (31.5, 3.2) and (33.0, 3.2) and between (16.0, 3.7) and (17.0, 3.7)	1
	Worst acceptable line drawn.	1
	Steepest or shallowest possible line that passes through all the error bars.	
	All error bars must be plotted.	
2(c)(iii)	Gradient must be negative. Gradient determined with clear substitution of data into $\Delta y/\Delta x$ ; distance between data points must be greater than half the length of the drawn line.	1
	Gradient determined of worst acceptable line with clear substitution of data into $\Delta y/\Delta x$ ; uncertainty = (gradient of line of best fit – gradient of worst acceptable line) or uncertainty = $\frac{1}{2}$ (steepest worst line gradient – shallowest worst line gradient)	1
2(c)(iv)	y-intercept determined by substitution of correct point with consistent unit of time into $y = mx + c$	1
	<i>y</i> -intercept of worst acceptable line determined by substitution into $y = mx + c$ .	1
	uncertainty = $y$ -intercept of line of best fit — $y$ -intercept of worst acceptable line, or uncertainty = $\frac{1}{2}$ (steepest worst line $y$ -intercept — shallowest worst line $y$ -intercept)	
	Do not accept ecf from false origin method.	

Question	Answer	Marks
2(d)(i)	$K$ determined using gradient <b>and</b> $K$ and $\Theta$ given to 3 or 4 sf. $K = -\frac{1}{\text{gradient}}$	1
	$\theta$ determined using $y$ -intercept <b>and</b> $K$ and $\theta$ given with units with appropriate powers of ten $\theta_0 = e^{y$ -intercept} + 18.5 Unit of $K$ : min or minute(s) unit of $\theta$ : °C	1
2(d)(ii)	Absolute uncertainty determined with clear method shown. $\Delta\theta_0 = \left(e^{\max y\text{-intercept}} + 19\right) - \left(e^{y\text{-intercept}} + 18.5\right)$ OR $\Delta\theta_0 = \left(e^{y\text{-intercept}} + 18.5\right) - \left(e^{\min y\text{-intercept}} + 18\right)$ OR $\Delta\theta_0 = \frac{\left(e^{\max y\text{-intercept}} + 19\right) - \left(e^{\min y\text{-intercept}} + 18\right)}{2}$	1
2(e)	$t$ determined to a minimum of 2sf from <b>(c)(iii)</b> and <b>(c)(iv)</b> OR <b>(d)(i)</b> with correct substitution <u>and</u> correct power of ten. $t = \frac{\ln(25.0 - 18.5) - y \text{-intercept}}{\text{gradient}}$ OR $t = -K \times \left(\ln(25.0 - 18.5) - y \text{-intercept}\right)$ OR $t = -K \times \ln\left(\frac{25.0 - 18.5}{\theta_0 - 18.5}\right)$	1